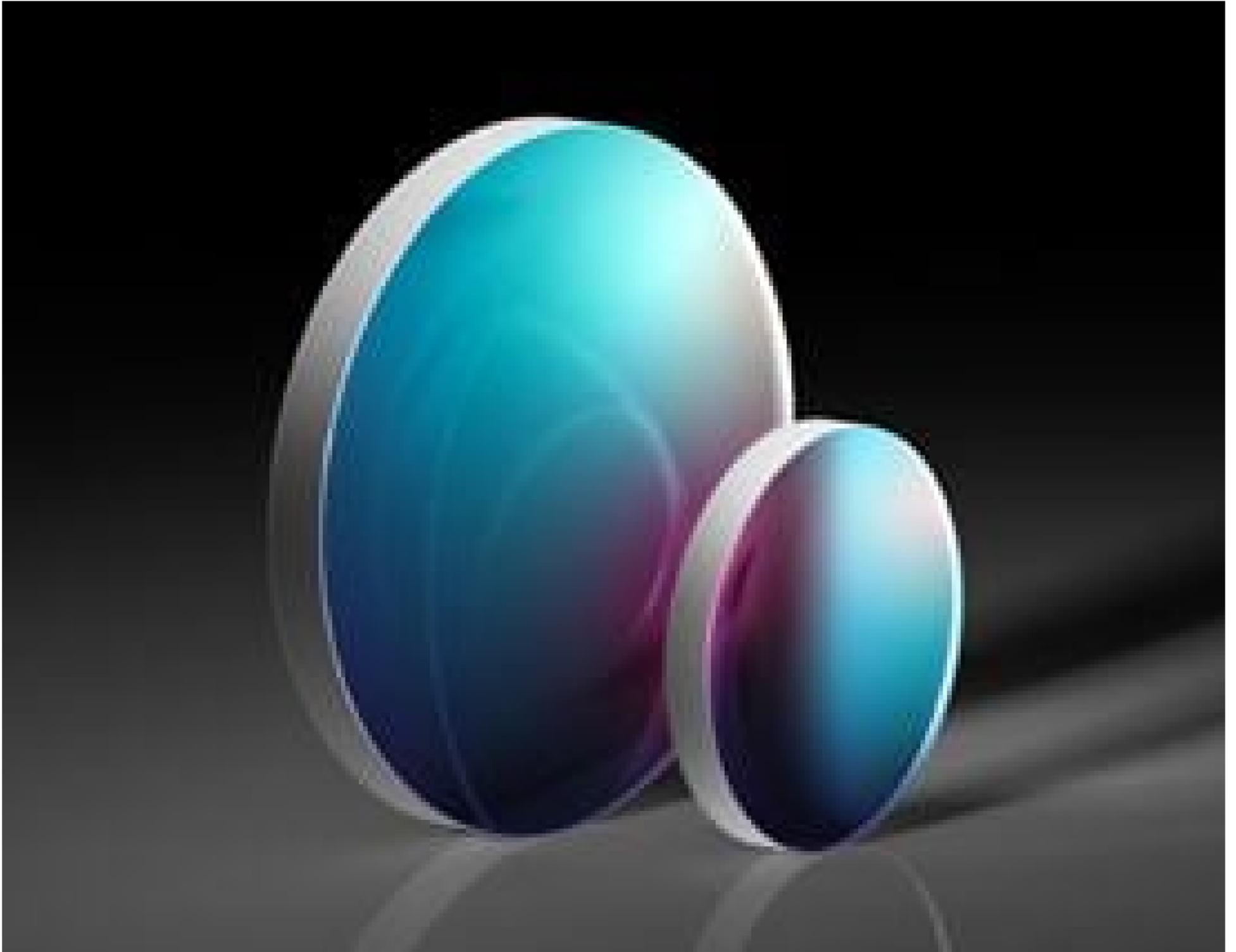


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**TECHSPEC® 25.4mm Dia., 1mm Thick, 532nm, Nd:YAG Laser Line Beam Sampler**



TECHSPEC® Thin Nd:YAG Laser Line Beam Samplers

Stock **#29-020** **20+ In Stock**

⊖ 1 ⊕ ₹9,022

**ADD TO CART**

Volume Pricing	
Qty 1-5	₹9,022 each
Qty 6-25	₹8,142 each
Qty 26-49	₹7,262 each
Need More?	<a href="#">Request Quote</a>

Product Downloads

**General**

Beam Sampler

Type:

**Physical & Mechanical Properties**

1.00 ±0.10

Thickness (mm):

25.40 +0.00/-0.10

Diameter (mm):

90 Clear Aperture (%):

<0.50 Parallelism (arcmin):

## Optical Properties

**Fused Silica** (Coming 7980) Substrate:

1.458 Index of Refraction ( $n_d$ ):

20-10 Surface Quality:

0 ±5 Angle of Incidence (°):

Laser V-Coat (532nm) Coating:

532 Design Wavelength DWL (nm):

$R_{abs} < 0.25\%$  @ 532nm @ 0 ±5° AOI Coating Specification:

10 J/cm<sup>2</sup> @ 532nm, 20ns, 20Hz Damage Threshold, By Design:

0.167 @ 632.8nm Transmitted Wavefront Distortion:

## Regulatory Compliance

Compliant RoHS 2015:

View Certificate of Conformance:

Compliant Reach 240:

United States Country of Origin:

Edmund Optics India Private Limited Imported By:

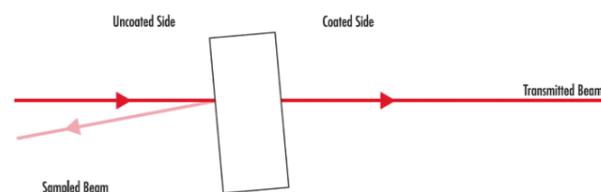
## Product Details

- Thin 1mm Design for Space and Weight Constrained Applications
- Uncoated First Surface Provides Fresnel Reflection
- AR Coated Second Surface Provides High Transmission
- High Laser Damage Threshold to Prevent Laser Ablation

TECHSPEC® Thin Nd:YAG Laser Line Beam Samplers are designed to isolate a small portion of incident beams via Fresnel reflection and anti-reflection properties for beam monitoring purposes. These beam samplers are designed with a 1mm thickness to facilitate applications where space and weight constraints are critical. Additionally, an anti-reflection (AR) coating with a high damage threshold on surface two maximizes transmission and reduces ghost reflections. These second surface coated beam samplers are available in laser line coatings including 266nm, 355nm, 532nm, and 1064nm wavelengths. TECHSPEC® Thin Nd:YAG Laser Line Beam Samplers feature a UV Fused Silica substrate which provides excellent transmission from the UV to the IR and a low coefficient of thermal expansion. These beam samplers are ideal for applications where monitoring beam power, wavefront distortion, and optical losses are required.

**Note:** TECHSPEC® Thin Nd:YAG Laser Line Beam Samplers can be used with [Laser Measurement](#) products to monitor beam properties, such as beam power and beam profile, in real time.

## Technical Information



Laser Line Beam Sampler

## Compatible Mounts